

PRODUCT / PROCESS CHANGE NOTIFICATION

1. PCN basic data

1.1 Company		STMicroelectronics International N.V
1.2 PCN No.	MDG/22/13539	
1.3 Title of PCN	ST Shenzhen (China) Assy & Test line upgrade for CMOS F9V Automotive grade EEPROM products in SO8N	
1.4 Product Category	CMOS F9V Automotive EEPROM product in SO8N M95M04-DWMN3TP/V	
1.5 Issue date	2022-06-30	

2. PCN Team

2.1 Contact supplier	
2.1.1 Name	ROBERTSON HEATHER
2.1.2 Phone	+1 8475853058
2.1.3 Email	heather.robertson@st.com
2.2 Change responsibility	
2.2.1 Product Manager	Benoit RODRIGUES
2.1.2 Marketing Manager	Philippe GANIVET
2.1.3 Quality Manager	Rita PAVANO

3. Change

3.1 Category	3.2 Type of change	3.3 Manufacturing Location
Machines	(Not Defined)	ST Shenzhen (China)

4. Description of change

	Old	New
4.1 Description	Automotive grade EEPROM products in SO8N are widely used in high volume at all automotive customers and in all automotive applications. To maintain high level of service and to support high volume production on the long-term, ST has decided to switch Assembly & Test from High Density (HD) strip test line...	...to Super High Density (SHD) strip test line.
4.2 Anticipated Impact on form,fit, function, quality, reliability or processability?	- Form: visual on package top side / backside - Fit: no change - Function: no change	

5. Reason / motivation for change

5.1 Motivation	The strategy of the STMicroelectronics Memory division is to support our customers on product and service quality on a long-term basis. In line with this commitment, this change will secure long term availability and automotive SO8N capacity while improving product manufacturing quality.
5.2 Customer Benefit	QUALITY IMPROVEMENT

6. Marking of parts / traceability of change

6.1 Description	N/A
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7. Timing / schedule

7.1 Date of qualification results	2022-07-15
7.2 Intended start of delivery	2023-01-01
7.3 Qualification sample available?	Upon Request

8. Qualification / Validation

8.1 Description	
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8.2 Qualification report and qualification results	In progress	Issue Date	
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9. Attachments (additional documentations)

13539 Public product.pdf 13539 PCN F9V SO8N HD to SHD.pdf
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10. Affected parts

10. 1 Current		10.2 New (if applicable)
10.1.1 Customer Part No	10.1.2 Supplier Part No	10.1.2 Supplier Part No
	M95M04-DWMN3TP/V	



Public Products List

Public Products are off the shelf products. They are not dedicated to specific customers, they are available through ST Sales team, or Distributors, and visible on ST.com

PCN Title : ST Shenzhen (China) Assy & Test line upgrade for CMOS F9V Automotive grade EEPROM products in SO8N

PCN Reference : MDG/22/13539

Subject : Public Products List

Dear Customer,

Please find below the Standard Public Products List impacted by the change.

M95M04-DWMN3TP/V		
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